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DATE MAILED: 09/09/2003

PPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO	
10/046,741	01/17/2002	Yoshinobu Ono	3885-0103P	2546	
2292	7590 09/09/2003				
BIRCH STEWART KOLASCH & BIRCH			EXAMINER		
PO BOX 747 FALLS CHURCH, VA 22040-0747		·	MULPURI, SAVITRI		
			ART UNIT	PAPER NUMBER	
			2812		

Please find below and/or attached an Office communication concerning this application or proceeding.

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Application No. 10/046,741

Applicant(s)

Ono et al

Office Action Summary

Examiner Savitri Mulpuri Art Unit 2812

	The MAILING DATE of this communication appears of	on the cover she	et with	the correspondence address		
	for Reply					
THE	MAILING DATE OF THIS COMMUNICATION.			_		
	sions of time may be available under the provisions of 37 CFR 1.136 (a). In r ng date of this communication.	no event, however, ma	sy a reply b	e timely filed after SIX (6) MONTHS from the		
- If NO - Failur - Any r	period for reply specified above is less than thirty (30) days, a reply within the period for reply is specified above, the maximum statutory period will apply as a to reply within the set or extended period for reply will, by statute, cause the reply received by the Office later than three months after the mailing date of the patent term adjustment. See 37 CFR 1.704(b).	nd will expire SIX (6) Ne application to become	MONTHS fi 10 ABANDO	om the mailing date of this communication. ONED (35 U.S.C. § 133).		
Status	• • • • •					
1) 💢	Responsive to communication(s) filed on Jun 19, 20	003		<u> </u>		
2a) 💢	This action is FINAL . 2b) ☐ This acti	ion is non-final.				
3) 🗆		s application is in condition for allowance except for formal matters, prosecution as to the merits is accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11; 453 O.G. 213.				
Dispos	ition of Claims					
4) 💢	Claim(s) <u>1-6</u>			is/are pending in the application.		
	4a) Of the above, claim(s)			is/are withdrawn from consideration.		
5) 🗆	Claim(s)			is/are allowed.		
6) 💢	Claim(s) <u>1-6</u>			is/are rejected.		
7) 🗆	Claim(s)		<u> </u>	is/are objected to.		
8) 🗆	Claims	are	subject	to restriction and/or election requirement.		
Applic	ation Papers					
9) 🗆	The specification is objected to by the Examiner.					
10)	The drawing(s) filed on is/are	a) 🗆 accepted	d or b)(\square objected to by the Examiner.		
	Applicant may not request that any objection to the d	rawing(s) be hel	d in abe	yance. See 37 CFR 1.85(a).		
11)	The proposed drawing correction filed on	is:	a) 🗆 a	approved b) \square disapproved by the Examiner.		
	If approved, corrected drawings are required in reply t	to this Office act	ion.			
12)	The oath or declaration is objected to by the Exami	ner.				
	y under 35 U.S.C. §§ 119 and 120					
		riority under 35	U.S.C.	§_1·19(a)-(d) or (f).		
a) (□ All b)□ Some* c)□ None of:					
	1. Certified copies of the priority documents have been received.					
	2. Certified copies of the priority documents have been received in Application No					
# (3. Copies of the certified copies of the priority de application from the International Bure.	au (PCT Rule 1	7.2(a)).			
		priority under t	JJ U.J.	C. 33 120 dild/or 121.		
	ment(s) Notice of References Cited (PTO-892)	4) Interview Sur	nmary (PT)	0-413) Paper No(s)		
2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 5) Notice of Informal Patent Application (PTO-152)						
3) 🔲 I	3) Information Disclosure Statement(s) (PTO-1449) Paper No(s) 6) Uther:					
5)	Claim(s)	a) accepted rawing(s) be held is: to this Office act ner. riority under 35 e been received been received au (PCT Rule 1) e certified copie priority under 31 application ha priority under 31 application has priority under 32 application has pr	subject d or b) d in abe a) a ion. U.S.C. d. d in App been re 7.2(a)). es not re 35 U.S. is been 35 U.S.	is/are allowed. is/are rejected. is/are objected to. to restriction and/or election requirement. objected to by the Examiner. yance. See 37 CFR 1.85(a). approved b) disapproved by the Examine \$_119(a)-(d) or (f). oblication No. ecceived in this National Stage ecceived. C. § 119(e). received. C. §§ 120 and/or 121.		

DETAILED ACTION

Claims 1-4 are rejected under 35 U.S.C. 103(a) as being unpatentable over Admitted prior art in combination in Narui.

Rejection si maintained same as in paper no. 8 mailed on 12/20/03.

Claims 1-6 are rejected under 35 U.S.C. 102(b) as being anticipated by Narui.

Rejection si maintained same as in paper no. 8 mailed on 12/20/03.

Applicant's arguments filed ON 6/19/03 have been fully considered but they are not persuasive. Applicant argues that Admitted prior art in page 1-2 of the instant specification fails disclose or suggest a fabrication step in which second layer of higher Al content is grown on first layer of lower Al content at slower growth rate than that used to grow the first layer, as in the present invention. However, secondary reference Narui teaches that AlGaAs with higher Al content is grown at a low growth rate of 0.16 nm/sec with reduced roughness and reduced defects. Modified invention of Admitted prior art as modified by the teaching Narui results smooth surface with reduced defects.

Applicant argues that Narui is directed to inhibiting the occurrence of defects or surface roughness and addresses defects which occur when AlGaAs layer is grown on stripe-like ridges formed on AlGaAs, when the ridges are narrow, limited region and the existence of a facet other

Art Unit:

than the (100) surface is essential. However such disclosure in the invention of Narui is not relevant to the recited claims.

Applicant clearly stated that the teaching of Narui suggesting to inhibit the occurrence of defects the growth rate must be made lower for the growth of AlGaAs having higher Al content setting growth rate 0.16/sec., which is exactly same as the crux of the instant claimed invention.

Applicant argues that Narui fails to disclose any difference in the growth rate of AlGaAs layers of higher or lower Al content as in the method of the present invention and fails mention any relationship anything regarding the relationship of the growth rates of these two layers having different Al content. However, Narui teaches successively growing GaAs layer on GaAs substrate; growing plurality of AlGaAs layers AlGaAs with Al content 0.45, algas with Al content 0.14, Algas with Al content 0.45, Algas with Al content 0.45 and Algas with Al content 0.45, wherein AlGaAs greater than 0.4 is grown at lower growth rate 0.16 nm/ sec to roughness and in turn reduce the roughness (see abstract and fig. 6 and see the whole document). AlGaAs layer 1 and 2 as first set of buffer layer and AlGaAs 3-5 are second set of buffer layers, where in Al content in bottom layer of second set of buffer layers is higher than al content in top buffer layer of first set buffer layer.

Conclusively, Narui suggests to inhibit the occurrence of defects, the growth rate must be made lower for the growth of AlGaAs having higher Al content e.g., setting growth rate 0.16/sec., which is exactly same as the crux of the instant claimed invention.

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THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time

policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE

MONTHS from the mailing date of this action. In the event a first reply is filed within TWO

MONTHS of the mailing date of this final action and the advisory action is not mailed until after

the end of the THREE-MONTH shortened statutory period, then the shortened statutory period

will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR

1.136(a) will be calculated from the mailing date of the advisory action. In no event, however,

will the statutory period for reply expire later than SIX MONTHS from the mailing date of this

final action.

Any inquiry concerning this communication or earlier communications from the examiner

should be directed to S. Mulpuri whose telephone number is 703-305-5184. The fax phone

number for the organization where this application or proceeding is assigned is 703-308-7722.

Any inquiry of a general nature or relating to the status of this application or proceeding

should be directed to the receptionist whose telephone number is 703-308-0956.

AVITRI MULPURI

PRIMARY EXAMINER

SM

9/5/03